P27064.P01 SERIAL NO. ATTY. DOCKET NO. FORM PTO-1449 (Modified) 10/709,362 P27064 LIST OF PATENTS AND PUBLICATIONS POR APPLICANT: APPLICANT'S INFORMATION DISCLOSURE David J. Hathaway, et al **STATEMENT** OCT 1 4 2005 FILING DATE: **GROUP:** (Use several sheets if necessary) PARADELS. PATENT DOCUMENTS 2863 REFERENCE DESIGNATION FILING DATE **DOCUMENT EXAMINER** (IF APPRO.) **CLASS** SUBCLASS NAME NUMBER DATE **INITIALS** FOREIGN PATENT DOCUMENTS **TRANSLATION DOCUMENT** SUBCLASS **CLASS** COUNTRY DATE NUMBER YES NO OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.) Aseem Agarwal, et al., "Statistical Timing Analysis for Intra-Die Process Variations with Spatial Correlations," ICCAD '03, November 11-13, 2003, pages 900-907. Michael Orshansky, et al., "Impact of Spatial Intrachip Gate Length Variability on the Performance of High-Speed Digital Circuits," IBEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, Vol. 21, No.5, May 2002, pages 544-553. 12/20/05 DATE CONSIDERED EXAMINER

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.